

**Notice of References Cited**

Application/Control No.

10/002,864

Applicant(s)/Patent Under  
Reexamination  
HOFFMANN ET AL.

Examiner

Yelena G. Gakh, Ph.D.

Art Unit

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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B	US-4,851,352	07-1989	Fischer et al.	436/42
C	US-			
D	US-			
E	US-			
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H	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

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P					
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R					
S					
T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U		Sherman et al. "Stoichiometry and chemical metrology: Karl Fischer reagent; Accreditation and Quality Assurance, May 1999, v. 4, No. 6, pp. 230-234, Abstract and text search from Google (see page link below)
V		<a href="http://www.springerlink.com/app/home/contribution.asp?wasp=d48072eewh4uvl493q7p&amp;referrer=parent&amp;backto=issue,6,16;journal,53,83;linkingpublicationresults,1:100393,1">http://www.springerlink.com/app/home/contribution.asp?wasp=d48072eewh4uvl493q7p&amp;referrer=parent&amp;backto=issue,6,16;journal,53,83;linkingpublicationresults,1:100393,1</a>
W		
X		

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